

**Search Notes**

Application/Control No.

10/665,064

Examiner

Rick K. Chang

Applicant(s)/Patent under  
Reexamination

YEN ET AL.

Art Unit

3729

**SEARCHED**

Class	Subclass	Date	Examiner
29	739,740,8 32,281.1	11/30/2005	RC
901	40		
294	64.1,2		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
east search	12/1/2005	RC